

**Search Notes**

Application/Control No.

10/630,795

Examiner

Jinhee J. Lee

Applicant(s)/Patent under  
Reexamination

ALZNAUER ET AL.

Art Unit

2831

**SEARCHED**

| Class | Subclass                   | Date       | Examiner |
|-------|----------------------------|------------|----------|
| 174   | 152R,<br>152g, 360,<br>362 | 10/26/2006 | LEE      |
|       |                            |            |          |
|       |                            |            |          |
|       |                            |            |          |
|       |                            |            |          |
|       |                            |            |          |
|       |                            |            |          |
|       |                            |            |          |
|       |                            |            |          |
|       |                            |            |          |
|       |                            |            |          |
|       |                            |            |          |
|       |                            |            |          |
|       |                            |            |          |

**INTERFERENCE SEARCHED**

| Class | Subclass | Date       | Examiner |
|-------|----------|------------|----------|
| 174   | as above | 10/26/2006 | LEE      |
|       |          |            |          |
|       |          |            |          |
|       |          |            |          |

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

|  | DATE | EXMR |
|--|------|------|
|  |      |      |
|  |      |      |
|  |      |      |
|  |      |      |
|  |      |      |
|  |      |      |
|  |      |      |
|  |      |      |
|  |      |      |
|  |      |      |
|  |      |      |
|  |      |      |
|  |      |      |
|  |      |      |